

Appln. No. 10/527,108  
Amdt. dated June 7, 2006  
Reply to Office Action dated April 4, 2006

ABSTRACT

The invention relates to a test device for testing an integrated circuit called test circuit, comprising a plurality of housings intended to be tested in a printed circuit called main circuit. The device comprises an insulating membrane of soft material having two opposite surfaces covered by two conductive layers interconnected by via holes and intended to be in contact with the test circuit and the main circuit respectively, under the influence of a pressure exerted during the test between the test circuit and the main circuit pressing the test device. Protrusions are arranged on at least one of the two layers in a predefined pattern as a function of said pins, tabs, pads etc. of the test circuit so as to ensure a contact quality between said layer and the circuit (to be tested or the main circuit) having contact with said layer under the influence of said pressing action.